

Notice of References Cited	Application/Control No. 10/067,425	Applicant(s)/Patent Under Reexamination VAN VEEN ET AL.	
	Examiner Scott B. Geyer	Art Unit 2829	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,235,552	05-2001	Kwon et al.	438/106
	B	US-6,492,737	12-2002	Imasu et al.	257/778
	C	US-6,225,206	05-2001	Jimarez et al.	438/616
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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